

February 2007

FDMS3672

N-Channel UltraFET Trench MOSFET

100V, **22A**, **23m** Ω

Features

- Max $r_{DS(on)} = 23m\Omega$ at $V_{GS} = 10V$, $I_D = 7.4A$
- Max $r_{DS(on)} = 29m\Omega$ at $V_{GS} = 6V$, $I_D = 6.6A$
- Typ Qg = 31nC at $V_{GS} = 10V$
- Low Miller Charge
- Optimized efficiency at high frequencies
- RoHS Compliant

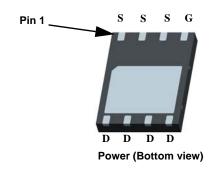


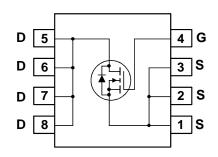
General Description

UltraFET devices combine characteristics that enable benchmark efficiency in power conversion applications. Optimized for $r_{DS(on)}$, low ESR, low total and Miller gate charge, these devices are ideal for high frequency DC to DC converters.

Application

■ DC - DC Conversion





MOSFET Maximum Ratings T_A = 25°C unless otherwise noted

Symbol	Parameter			Ratings	Units
V _{DS}	Drain to Source Voltage			100	V
V _{GS}	Gate to Source Voltage			±20	V
	Drain Current -Continuous (Package limited)	T _C = 25°C		22	
I _D	-Continuous (Silicon limited)	T _C = 25°C		41	^
	-Continuous	T _A = 25°C	(Note 1a)	7.4	A
	-Pulsed			30	
D	Power Dissipation	T _C = 25°C		78	W
P_D	Power Dissipation	T _A = 25°C	(Note 1a)	2.5	VV
T _J , T _{STG}	Operating and Storage Junction Temperature R	ange		-55 to +150	°C

Thermal Characteristics

$R_{\theta JC}$	Thermal Resistance, Junction to Case	1.6	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient (Note 1a)	50	C/VV

Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDMS3672	FDMS3672	Power 56	13"	12mm	3000 units

Electrical Characteristics $T_J = 25^{\circ}\text{C}$ unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Chara	acteristics					
BV _{DSS}	Drain to Source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0 V$	100			V
$\frac{\Delta BV_{DSS}}{\Delta T_{J}}$	Breakdown Voltage Temperature Coefficient	$I_D = 250\mu\text{A}$, referenced to 25°C		104		mV/°C
	Zero Gate Voltage Drain Current	V _{DS} = 80V,			1	^
DSS	Zero Gate voltage Drain Current	$V_{GS} = 0V$ $T_J = 55^{\circ}C$			10	μΑ
I _{GSS}	Gate to Source Leakage Current	$V_{GS} = \pm 20V, V_{DS} = 0V$			±100	nA

On Characteristics

V _{GS(th)}	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_{D} = 250 \mu A$	2	3.1	4	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	$I_D = 250\mu\text{A}$, referenced to 25°C		-11		mV/°C
		$V_{GS} = 10V, I_D = 7.4A$		19	23	
r _{DS(on)}	Drain to Source On Resistance	$V_{GS} = 6V, I_D = 6.6A$		24	29	mΩ
	$V_{GS} = 10V, I_D = 7.4A, T_J = 125^{\circ}C$		33	40		
9 _{FS}	Forward Transconductance	$V_{DS} = 10V, I_D = 7.4A$		20		S

Dynamic Characteristics

C _{iss}	Input Capacitance	V 50V V 0V	2015	2680	pF
C _{oss}	Output Capacitance	$V_{DS} = 50V, V_{GS} = 0V,$ f = 1MHz	210	280	pF
C _{rss}	Reverse Transfer Capacitance		90	135	pF
R_q	Gate Resistance	f = 1MHz	1.3		Ω

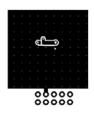
Switching Characteristics

t _{d(on)}	Turn-On Delay Time	$V_{DD} = 50V, I_{D} = 7.4A$ $V_{GS} = 10V, R_{GEN} = 6\Omega$		23	37	ns
t _r	Rise Time			11	20	ns
t _{d(off)}	Turn-Off Delay Time			36	58	ns
t _f	Fall Time			8	16	ns
Q_q	Total Gate Charge at 10V	V _{GS} = 0V to 10V		31	44	nC
Q_q	Total Gate Charge at 4.5V	$V_{GS} = 0V \text{ to } 4.5V$ $V_{DD} = 50V$ $I_{D} = 7.4A$				nC
Q_{gs}	Gate to Source Gate Charge	I _D = 7.4A		9.5		nC
Q _{nd}	Gate to Drain "Miller" Charge			8		nC

Drain-Source Diode Characteristics

V_{SD}	Source to Drain Diode Forward Voltage	V _{GS} = 0V, I _S = 7.4A (Note 2)		0.8	1.2	V
t _{rr}	Reverse Recovery Time	L = 7.44 di/dt = 1004/vo		52	78	ns
Q _{rr}	Reverse Recovery Charge	$I_F = 7.4A$, di/dt = 100A/ μ s		101	152	nC

Notes:
 1: R_{0JA} is determined with the device mounted on a 1in² pad 2 oz copper pad on a 1.5 x 1.5 in. board of FR-4 material. R_{0JC} is guaranteed by design while R_{0CA} is determined by the user's board design.



a. 50°C/W when mounted on a 1 in² pad of 2 oz copper

b. 125°C/W when mounted on a minimum pad of 2 oz copper



2: Pulse Test: Pulse Width < $300\mu s$, Duty cycle < 2.0%.

Typical Characteristics T_J = 25°C unless otherwise noted

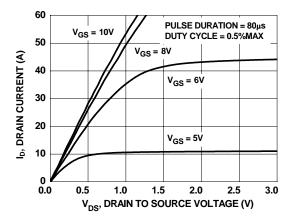


Figure 1. On-Region Characteristics

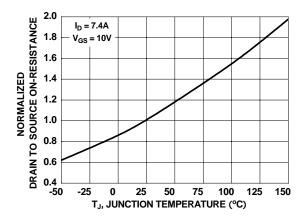


Figure 3. Normalized On-Resistance vs Junction Temperature

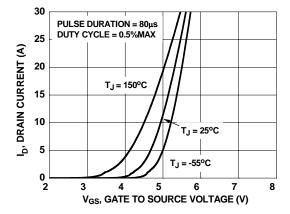


Figure 5. Transfer Characteristics

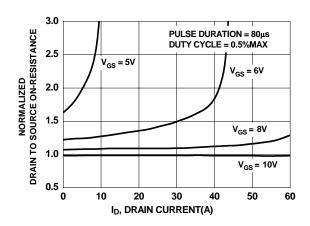


Figure 2. Normalized On-Resistance vs Drain Current and Gate Voltage

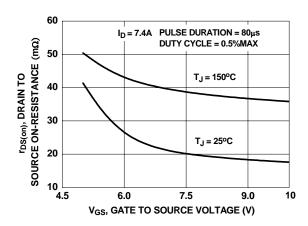


Figure 4. On-Resistance vs Gate to Source Voltage

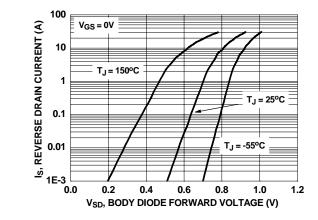


Figure 6. Source to Drain Diode Forward Voltage vs Source Current

Typical Characteristics $T_J = 25^{\circ}C$ unless otherwise noted

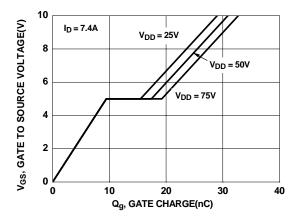


Figure 7. Gate Charge Characteristics

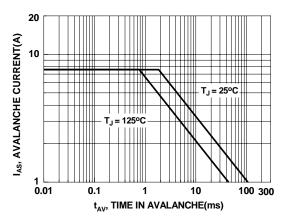


Figure 9. Unclamped Inductive Switching Capability

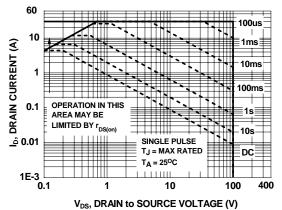


Figure 11. Forward Bias Safe Operating Area

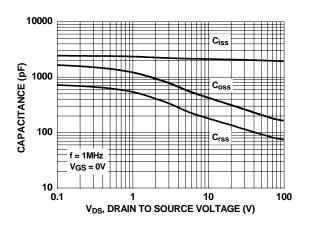


Figure 8. Capacitance vs Drain to Source Voltage

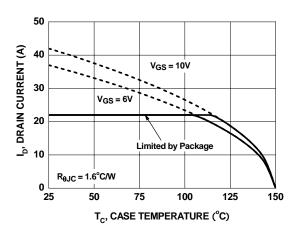


Figure 10. Maximum Continuous Drain Current vs Case Temperature

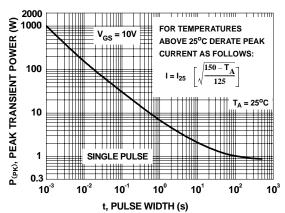


Figure 12. Single Pulse Maximum Power Dissipation

Typical Characteristics T_J = 25°C unless otherwise noted

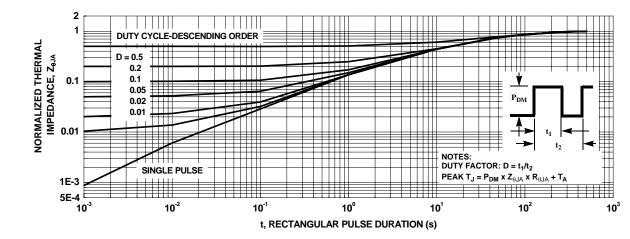
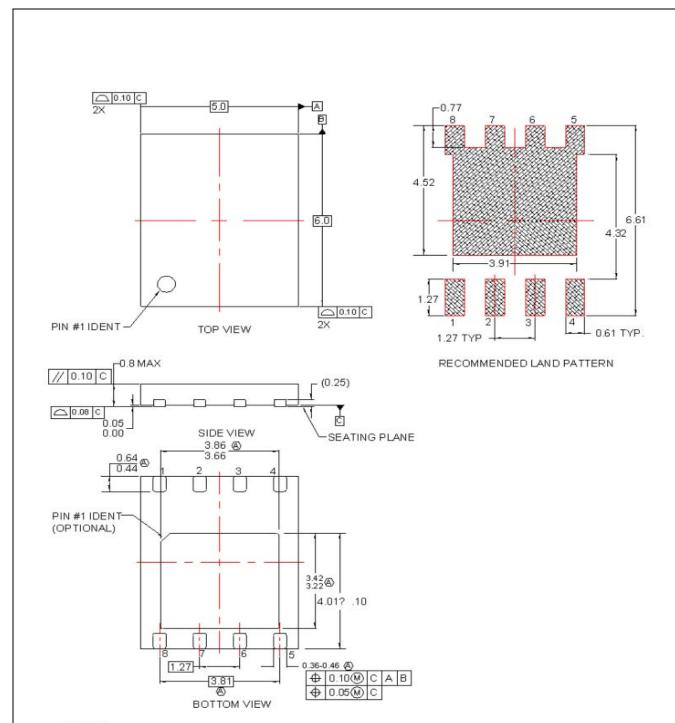


Figure 13. Transient Thermal Response Curve



NOTES:

- ODES NOT FULLY CONFORM TO JEDEC REGISTRATION, MO-229. DATED 11/2001.
- B. DIMENSIONS ARE IN MILLIMETERS.
- C. DIMENSIONS AND TOLERANCES PER ASME Y14.5M, 1994
- D. TERMINALS 5,6,7 AND 8 ARE TIED TO THE EXPOSED PADDLE

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